

# MOS FIELD EFFECT TRANSISTOR 2SK3572

## SWITCHING N-CHANNEL POWER MOS FET

#### **DESCRIPTION**

The 2SK3572 is N-channel MOS FET device that features a low on-state resistance and excellent switching characteristics, designed for low voltage high current applications such as DC/DC converter with synchronous rectifier.

#### **FEATURES**

- 4.5 V drive available
- Low on-state resistance

RDS(on)1 = 5.7 m $\Omega$  MAX. (VGS = 10 V, ID = 40 A)

• Low gate charge

 $Q_G = 32 \text{ nC TYP.}$  (VDD = 16 V, VGS = 10 V, ID = 80 A)

- Built-in gate protection diode
- Surface mount device available

**Note** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1%

### **★ ORDERING INFORMATION**

PART NUMBER	PACKAGE
2SK3572	TO-220AB
2SK3572-S	TO-262
2SK3572-ZK	TO-263
2SK3572-Z	TO-220SMD Note

Note TO-220SMD package is produced only in Japan.

### ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	20	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	I <sub>D(DC)</sub>	±80	Α
Drain Current (pulse) Note	D(pulse)	±300	Α
Total Power Dissipation (T <sub>A</sub> = 25°C)	P <sub>T1</sub>	1.5	W
Total Power Dissipation (Tc = 25°C)	P <sub>T2</sub>	52	W
Channel Temperature	Tch	150	°C
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C

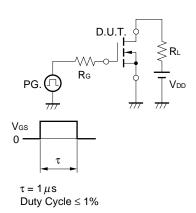
The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version. Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

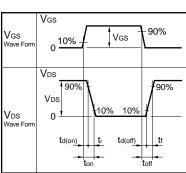


### ELECTRICAL CHARACTERISTICS (TA = 25°C)

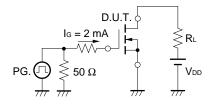
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			10	μΑ
Gate Leakage Current	Igss	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μΑ
Gate Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.5		2.5	V
Forward Transfer Admittance	yfs	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 40 A	15			S
Drain to Source On-state Resistance	RDS(on)1	V <sub>G</sub> S = 10 V, I <sub>D</sub> = 40 A		4.4	5.7	mΩ
	RDS(on)2	Vgs = 4.5 V, ID = 40 A		7.4	9.9	mΩ
Input Capacitance	Ciss	V <sub>DS</sub> = 10 V		1700		pF
Output Capacitance	Coss	Vgs = 0 V		700		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		250		pF
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 40 A		16		ns
Rise Time	<b>t</b> r	Vgs = 10 V		14		ns
Turn-off Delay Time	td(off)	$R_G = 10 \Omega$		50		ns
Fall Time	<b>t</b> f			12		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = 16 V		32		nC
Gate to Source Charge	Qgs	Vgs = 10 V		7.1		nC
Gate to Drain Charge	Q <sub>GD</sub>	ID = 80 A		7.7		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	IF = 80 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 80 A, VGS = 0 V		42		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		34		nC

### **TEST CIRCUIT 1 SWITCHING TIME**



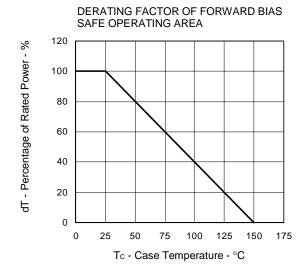


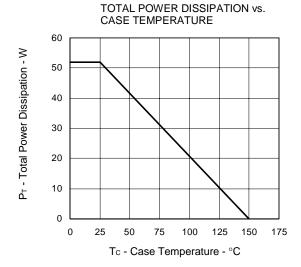
### **TEST CIRCUIT 2 GATE CHARGE**



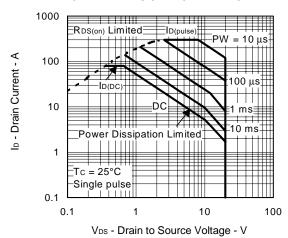


### TYPICAL CHARACTERISTICS (TA = 25°C)

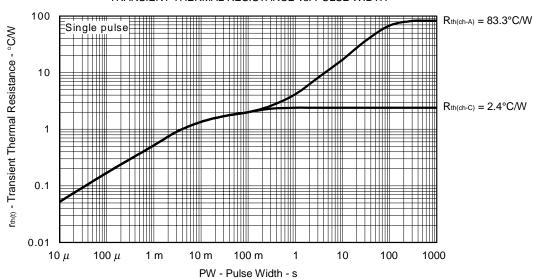




#### FORWARD BIAS SAFE OPERATING AREA

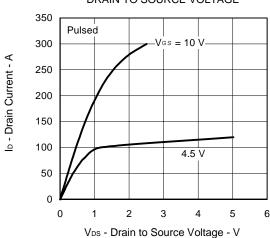


### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

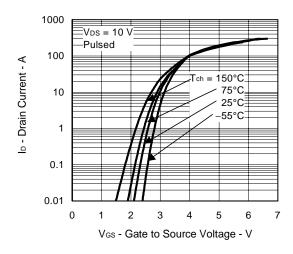


3

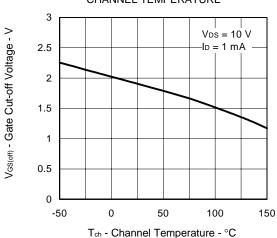
### DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



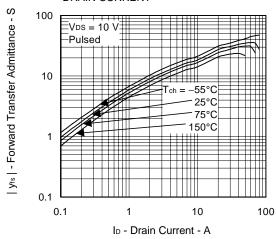
#### FORWARD TRANSFER CHARACTERISTICS



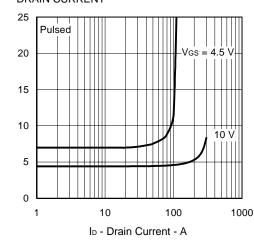
### GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



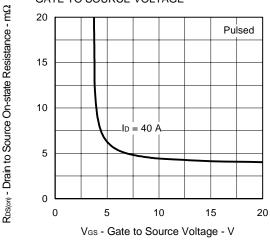
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



### DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



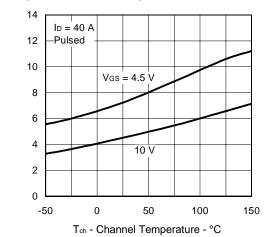
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



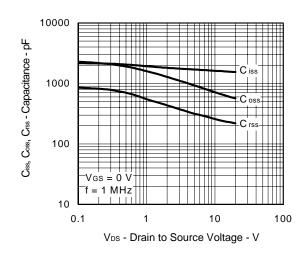
R<sub>DS(o1)</sub> - Drain to Source On-state Resistance - mΩ

RDS(m) - Drain to Source On-state Resistance - mΩ

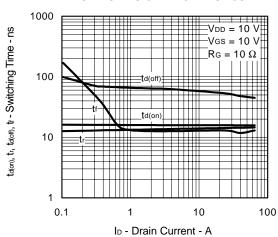
### DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



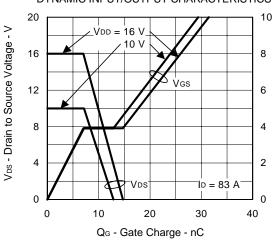
#### CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



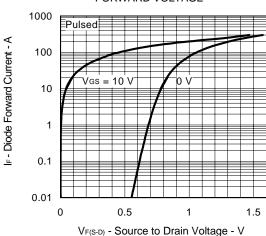
### SWITCHING CHARACTERISTICS



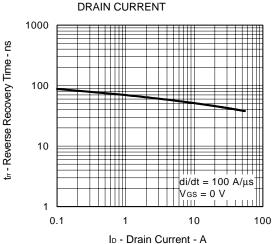
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



### SOURCE TO DRAIN DIODE FORWARD VOLTAGE



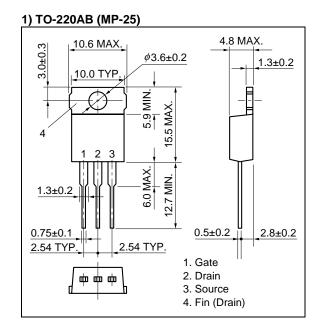
REVERSE RECOVERY TIME vs.

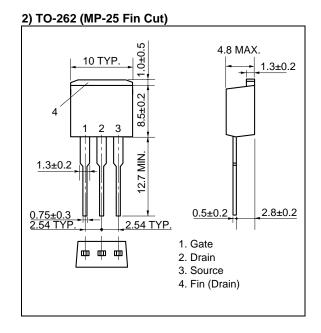


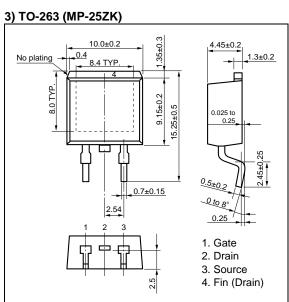
Ves - Gate to Source Voltage - V

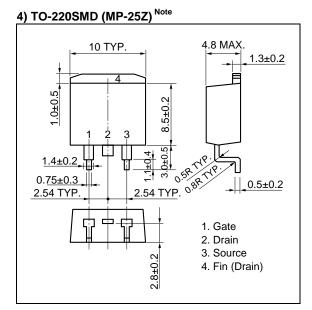


### **★ PACKAGE DRAWINGS (Unit: mm)**



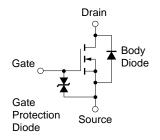






**Note** This package is produced only in Japan.

### **EQUIVALENT CIRCUIT**



**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

[MEMO]

- The information in this document is current as of September, 2002. The information is subject to change without notice. For actual design-in, refer to the latest publications of NEC's data sheets or data books, etc., for the most up-to-date specifications of NEC semiconductor products. Not all products and/or types are available in every country. Please check with an NEC sales representative for availability and additional information.
- No part of this document may be copied or reproduced in any form or by any means without prior written consent of NEC. NEC assumes no responsibility for any errors that may appear in this document.
- NEC does not assume any liability for infringement of patents, copyrights or other intellectual property rights of
  third parties by or arising from the use of NEC semiconductor products listed in this document or any other
  liability arising from the use of such products. No license, express, implied or otherwise, is granted under any
  patents, copyrights or other intellectual property rights of NEC or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative
  purposes in semiconductor product operation and application examples. The incorporation of these
  circuits, software and information in the design of customer's equipment shall be done under the full
  responsibility of customer. NEC assumes no responsibility for any losses incurred by customers or third
  parties arising from the use of these circuits, software and information.
- While NEC endeavours to enhance the quality, reliability and safety of NEC semiconductor products, customers
  agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize
  risks of damage to property or injury (including death) to persons arising from defects in NEC
  semiconductor products, customers must incorporate sufficient safety measures in their design, such as
  redundancy, fire-containment, and anti-failure features.
- NEC semiconductor products are classified into the following three quality grades:
  - "Standard", "Special" and "Specific". The "Specific" quality grade applies only to semiconductor products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of a semiconductor product depend on its quality grade, as indicated below. Customers must check the quality grade of each semiconductor product before using it in a particular application.
  - "Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots
  - "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)
  - "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

The quality grade of NEC semiconductor products is "Standard" unless otherwise expressly specified in NEC's data sheets or data books, etc. If customers wish to use NEC semiconductor products in applications not intended by NEC, they must contact an NEC sales representative in advance to determine NEC's willingness to support a given application.

(Note

- (1) "NEC" as used in this statement means NEC Corporation and also includes its majority-owned subsidiaries.
- (2) "NEC semiconductor products" means any semiconductor product developed or manufactured by or for NEC (as defined above).

M8E 00.4